TLVx316-Q1
10MHz、レール・ツー・レール入出力、低電圧、1.8V CMOSオペアンプ

1 特長

- **車載アプリケーションに対応**
- **下記内容でAEC-Q100認定済み**
  - デバイス温度グレード1: 動作時周囲温度範囲 –40°C～+125°C
  - デバイスHBM ESD分類レベル3A
  - デバイスCDM ESD分類レベルC5
- **ユニティ・ゲイン帯域幅**: 10MHz
- **低いI_Q**: 400µA/ch
  - 非常に優れた電力/帯域幅比
  - 温度や電源電圧にかかわらず安定したI_Q
- **広い電源電圧範囲**: 1.8V～5.5V
- **低ノイズ**: 1kHz時に12nV/√Hz
- **低い入力バイアス電流**: ±10pA
- **オフセット電圧**: ±0.75mV
- **ユニティ・ゲイン安定**
- **内部RFIおよびEMIフィルタ**
- **チャネル数**
  - TLV316-Q1: 1
  - TLV2316-Q1: 2
  - TLV4316-Q1: 4
- **拡張温度範囲**: -40℃～+125℃

2 アプリケーション

- **車載用アプリケーション**
  - ADAS (先進運転支援システム)
  - 車体エレクトロニクスおよび照明
  - 電流検出
  - バッテリ管理システム

3 概要

TLV316-Q1 (シングル)、TLV2316-Q1 (デュアル)、TLV4316-Q1 (クワッド)デバイスは、汎用低消費電力オペアンプのファミリです。レール・ツー・レール入力および出力、低い静止電流(標準値400µA/ch)と、10MHzの広い帯域幅を持ち合せており、非常に低ノイズ(1kHzにおいて12nV/√Hz)であるため、このファミリは優れた速度/電力比率を必要とする回路に適しています。入力バイアス電流が低いため、メガオーム単位のソース・インピーダンスを持つアプリケーションにも対応できます。TLVx316-Q1は入力バイアス電流が低いため、電流ノイズの発生もごく低く、高インピーダンスのセンサ・インターフェイスに魅力的な選択肢です。

TLVx316-Q1は堅牢に設計されており、ユニティ・ゲイン安定、RFIおよびEMI除去フィルタの内蔵、オーバードライブ状態で位相反転が発生しない、高い静電放電(ESD)保護(4kV HBM)という特長から、回路設計者が簡単に使用できます。

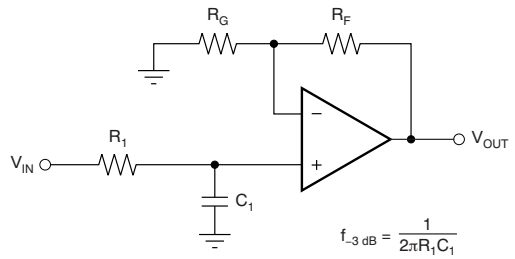
これらのデバイスは、最小1.8V (±0.9V)、最大5.5V (±2.75V)の低電圧での動作に最適化されています。低電圧CMOSオペアンプのポートフォリオへの新しい追加製品として、TLVx313-Q1およびTLVx314-Q1シリーズとともに、広範なアプリケーションの要求を満たす帯域幅、ノイズ、電力オプションのファミリを提供します。

製品情報(1)

型番	パッケージ	本体サイズ(公称)
TLV316-Q1	SOT-23 (5)	1.60mm×2.90mm
TLV2316-Q1	VSSOP (8)	3.00mm×3.00mm
TLV4316-Q1	TSSOP (14)	4.40mm×5.00mm

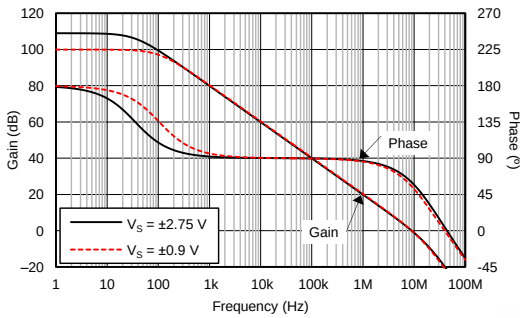
(1) 利用可能なすべてのパッケージについては、このデータシートの末尾にある注文情報を参照してください。

シングル・ポールのローパス・フィルタ



$$\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_G}\right)\left(\frac{1}{1 + sR_1C_1}\right)$$

10MHz帯域幅での低い消費電流(400µA/Ch)



目次

4 改訂履歴

Revision A (December 2016) から **Revision B** に変更 **Page**

- 誤字の修正、「*特長*」セクションで部品番号をTLV314、TLV2314、TLV4314からTLV316-Q1、TLV2316-Q1、TLV4316-Q1に変更 ... 1
- Changed values in the *Thermal Information: TLV4316-Q1* table to align with JEDEC standards. ... 8

2016年11月発行のものから更新 **Page**

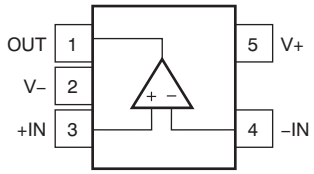
- 「*特長*」セクションでCDM ESD分類レベルをC6からC5に 変更 ... 1
- 「*製品情報*」表からSC70 (5)、SOIC (8)、SOIC (14)パッケージを 削除 ... 1
- Deleted the DCK (SC70) package from the TLV316-Q1 pinout diagram in the *Pin Configurations and Functions* section ... 4
- Deleted the DCK (SC70) pinout information from the *Pin Functions: TLV316-Q1* table in the *Pin Configurations and Functions* section ... 4
- Deleted D (SOIC) package from the TLV2316-Q1 pinout diagram in the *Pin Configurations and Functions* section ... 5
- Deleted the D (SOIC) package from TLV4316-Q1 pinout diagram in the *Pin Configurations and Functions* section ... 6
- Changed the *ESD Ratings* table from commercial to automotive specifications ... 7
- Changed the CDM ESD rating from ±1500 to ±750 in the *ESD Ratings* table ... 7
- Deleted the DCK (SC70) package from the *Thermal Information: TLV316-Q1* table in the *Specifications* section ... 8
- Changed the formatting of all *Thermal Information* table notes ... 8
- Deleted the D (SOIC) package from the *Thermal Information: TLV2316-Q1* table in the *Specifications* section ... 8
- Deleted the D (SOIC) package from the *Thermal Information: TLV4316-Q1* table in the *Specifications* section ... 8
- 削除 the static literature number in the SBOA128 application note reference in the *EMI Susceptibility and Input Filtering* section ... 16
- 削除 the static literature number in document reference in the *Layout Guidelines* section ... 19
- 変更 the layout example image (Figure 41) in *Layout Example* section ... 19
- 削除「*関連資料*」セクションでドキュメントの参照に含まれる静的な文書番号 ... 20

5 Device Comparison Table

DEVICE	NO. OF CHANNELS	PACKAGE-LEADS				
		DBV	DCK	D	DGK	PW
TLV316-Q1	1	5	5	—	—	—
TLV2316-Q1	2	—	—	8	8	—
TLV4316-Q1	4	—	—	14	—	14

6 Pin Configuration and Functions

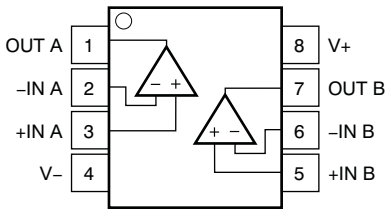
TLV316-Q1 DBV Package
5-Pin SOT-23
Top View



Pin Functions: TLV316-Q1

PIN		I/O	DESCRIPTION
NAME	NO.		
–IN	4	I	Inverting input
+IN	3	I	Noninverting input
OUT	1	O	Output
V–	2	—	Negative (lowest) supply or ground (for single-supply operation)
V+	5	—	Positive (highest) supply

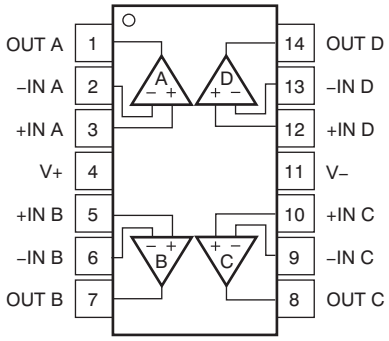
TLV2316-Q1 DGK Package
8-Pin VSSOP
Top View



Pin Functions: TLV2316 -Q1

PIN		I/O	DESCRIPTION
NAME	NO.		
–IN A	2	I	Inverting input, channel A
+IN A	3	I	Noninverting input, channel A
–IN B	6	I	Inverting input, channel B
+IN B	5	I	Noninverting input, channel B
OUT A	1	O	Output, channel A
OUT B	7	O	Output, channel B
V–	4	—	Negative (lowest) supply or ground (for single-supply operation)
V+	8	—	Positive (highest) supply

TLV4316-Q1 PW Package
14-Pin TSSOP
Top View



Pin Functions: TLV4316-Q1

PIN		I/O	DESCRIPTION
NAME	NO.		
–IN A	2	I	Inverting input, channel A
+IN A	3	I	Noninverting input, channel A
–IN B	6	I	Inverting input, channel B
+IN B	5	I	Noninverting input, channel B
–IN C	9	I	Inverting input, channel C
+IN C	10	I	Noninverting input, channel C
–IN D	13	I	Inverting input, channel D
+IN D	12	I	Noninverting input, channel D
OUT A	1	O	Output, channel A
OUT B	7	O	Output, channel B
OUT C	8	O	Output, channel C
OUT D	14	O	Output, channel D
V–	11	—	Negative (lowest) supply or ground (for single-supply operation)
V+	4	—	Positive (highest) supply

7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature (unless otherwise noted)(1)

			MIN	MAX	UNIT
Supply voltage				7	V
Signal input pins	Voltage(2)	Common-mode	(V–) – 0.5	(V+) + 0.5	V
		Differential		(V+) – (V–) + 0.2	
	Current(2)		–10	10	mA
Output short-circuit(3)			Continuous		mA
Temperature	Specified, T_A		–40	125	°C
	Junction, T_J			150	
	Storage, T_{stg}		–65	150	

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) Input pins are diode-clamped to the power-supply rails. Current limit input signals that can swing more than 0.5 V beyond the supply rails to 10 mA or less.
(3) Short-circuit to ground, one amplifier per package.

7.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002(1)	±4000	V
		Charged-device model (CDM), per AEC Q100-011	±750	

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V_S	Supply voltage	1.8		5.5	V
	Specified temperature range	–40		125	°C

7.4 Thermal Information: TLV316-Q1

THERMAL METRIC(1)		TLV316-Q1 DBV (SOT-23) 5 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	221.7	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	144.7	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	49.7	°C/W
ψ_{JT}	Junction-to-top characterization parameter	26.1	°C/W
ψ_{JB}	Junction-to-board characterization parameter	49.0	°C/W
$R_{\theta JC(bot)}$	Junction-to-case(bottom) thermal resistance	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

7.5 Thermal Information: TLV2316-Q1

THERMAL METRIC(1)		TLV2316-Q1 DGK (VSSOP) 8 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	186.6	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	78.8	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	107.9	°C/W
ψ_{JT}	Junction-to-top characterization parameter	15.5	°C/W
ψ_{JB}	Junction-to-board characterization parameter	106.3	°C/W
$R_{\theta JC(bot)}$	Junction-to-case(bottom) thermal resistance	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

7.6 Thermal Information: TLV4316-Q1

THERMAL METRIC(1)		TLV4316-Q1 PW (TSSOP) 14 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	117.8	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	46.5	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	59.6	°C/W
ψ_{JT}	Junction-to-top characterization parameter	5.3	°C/W
ψ_{JB}	Junction-to-board characterization parameter	59	°C/W
$R_{\theta JC(bot)}$	Junction-to-case(bottom) thermal resistance	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

7.7 Electrical Characteristics

at T_A = 25°C, R_L = 10 kΩ connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2 (unless otherwise noted); V_S (total supply voltage) = (V+) – (V–) = 1.8 V to 5.5 V

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFFSET VOLTAGE						
V_{OS}	Input offset voltage	V_S = 5 V		±0.75	±3	mV
		V_S = 5 V, T_A = –40°C to 125°C			±4.5	
dV_{OS}/dT	Drift	V_S = 5 V, T_A = –40°C to 125°C		±2		µV/°C
PSRR	Power-supply rejection ratio	V_S = 1.8 V – 5.5 V, V_{CM} = (V–)		±30	±175	µV/V
	Channel separation, dc	At dc		100		dB
INPUT VOLTAGE RANGE						
V_{CM}	Common-mode voltage range	V_S = 5.5 V	(V–) – 0.2		(V+) + 0.2	V
CMRR	Common-mode rejection ratio	V_S = 5.5 V, (V–) – 0.2 V < V_{CM} < (V+) – 1.4 V, T_A = –40°C to 125°C	72	90		dB
		V_S = 5.5 V, V_{CM} = –0.2 V to 5.7 V, T_A = –40°C to 125°C		75		
INPUT BIAS CURRENT						
I_B	Input bias current			±10		pA
I_{OS}	Input offset current			±10		pA
NOISE						
E_n	Input voltage noise (peak-to-peak)	V_S = 5 V, f = 0.1 Hz to 10 Hz		5		μV_{PP}
e_n	Input voltage noise density	V_S = 5 V, f = 1 kHz		12		$nV/\sqrt{Hz}$
i_n	Input current noise density	f = 1 kHz		1.3		$fA/\sqrt{Hz}$
INPUT IMPEDANCE						
Z_{ID}	Differential			2 || 2		$10^{16}\Omega$ || pF
Z_{IC}	Common-mode			2 || 4		$10^{11}\Omega$ || pF
OPEN-LOOP GAIN						
A_{OL}	Open-loop voltage gain	V_S = 5.5 V, (V–) + 0.05 V < V_O < (V+) – 0.05 V, R_L = 10 kΩ	100	104		dB
		V_S = 5.5 V, (V–) + 0.15 V < V_O < (V+) – 0.15 V, R_L = 2 kΩ		104		
FREQUENCY RESPONSE						
GBP	Gain bandwidth product	V_S = 5 V, G = 1		10		MHz
φ_m	Phase margin	V_S = 5 V, G = 1		60		Degrees
SR	Slew rate	V_S = 5 V, G = 1		6		V/µs
t_S	Settling time	To 0.1%, V_S = 5 V, 2-V step , G = 1, C_L = 100 pF		1		µs
t_{OR}	Overload recovery time	V_S = 5 V, V_{IN} × gain = V_S		0.8		µs
THD + N	Total harmonic distortion + noise(1)	V_S = 5 V, V_O = 0.5 V_{RMS}, G = 1, f = 1 kHz		0.008%		
OUTPUT						
V_O	Voltage output swing from supply rails	V_S = 1.8 V to 5.5 V, R_L = 10 kΩ			35	mV
		V_S = 1.8 to 5.5 V, R_L = 2 kΩ			125	
I_{SC}	Short-circuit current	V_S = 5 V		±50		mA
Z_O	Open-loop output impedance	V_S = 5 V, f = 10 MHz		250		Ω
POWER SUPPLY						
V_S	Specified voltage range		1.8		5.5	V
I_Q	Quiescent current per amplifier	V_S = 5 V, I_O = 0 mA, T_A = –40°C to 125°C		400	575	µA
TEMPERATURE						
T_A	Specified		–40		125	°C
T_{stg}	Storage		–65		150	°C

(1) Third-order filter; bandwidth = 80 kHz at –3 dB.

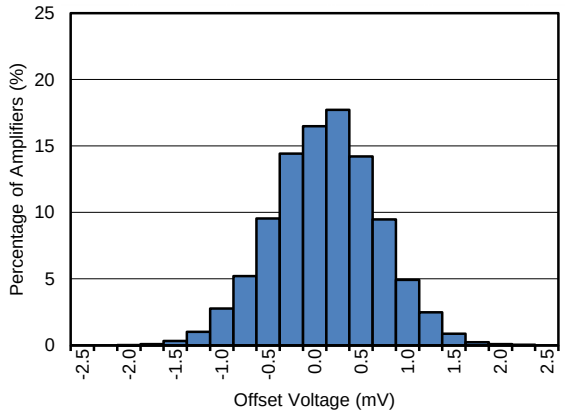
7.8 Typical Characteristics: Table of Graphs

表 1. Table of Graphs

TITLE	FIGURE
Offset Voltage Production Distribution	図 1
Offset Voltage vs Common-Mode Voltage	図 2
Open- Loop Gain and Phase vs Frequency	図 3
Input Bias and Offset Current vs Temperature	図 4
Input Voltage Noise Spectral Density vs Frequency	図 5
Quiescent Current vs Supply Voltage	図 6
Small-Signal Overshoot vs Load Capacitance	図 7
No Phase Reversal	図 8
Small-Signal Step Response	図 9
Large-Signal Step Response	図 10
Short-Circuit Current vs Temperature	図 11
Electromagnetic Interference Rejection Ratio Referred to Noninverting Input vs Frequency	図 12
Channel Separation vs Frequency	図 13

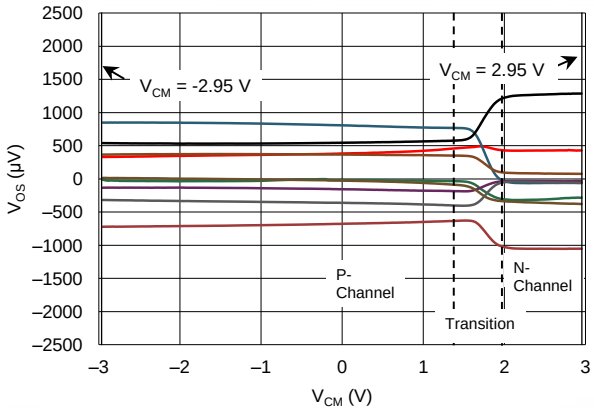
7.9 Typical Characteristics

at T_A = 25°C, V_S = 5.5 V, R_L = 10 kΩ connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2, (unless otherwise noted)



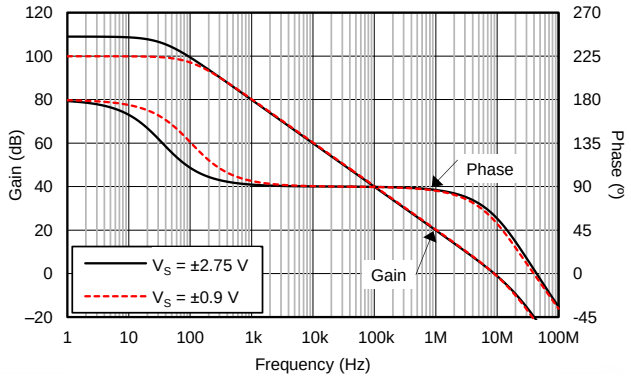
Distribution taken from 12551 amplifiers

図 1. Offset Voltage Production Distribution



V+ = 2.75 V　　V– = –2.75 V　　9 typical units shown

図 2. Offset Voltage vs Common-Mode Voltage



V_{CM} < (V+) – 1.4 V

図 3. Open-Loop Gain and Phase vs Frequency

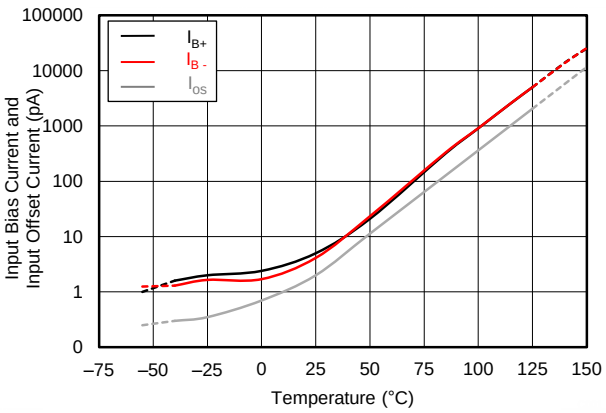


図 4. Input Bias and Offset Current vs Temperature

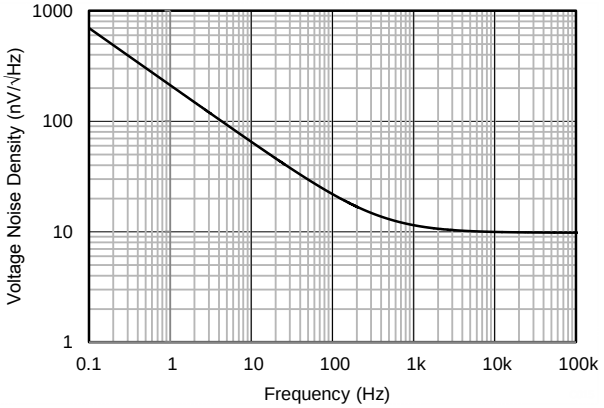


図 5. Input Voltage Noise Spectral Density vs Frequency

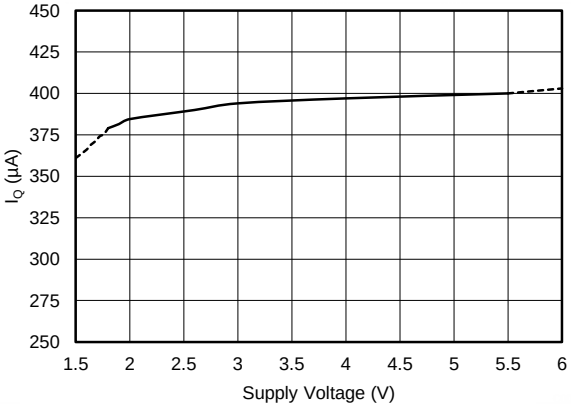
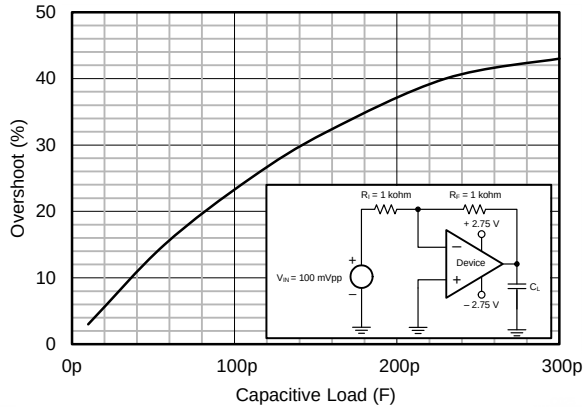


図 6. Quiescent Current vs Supply Voltage

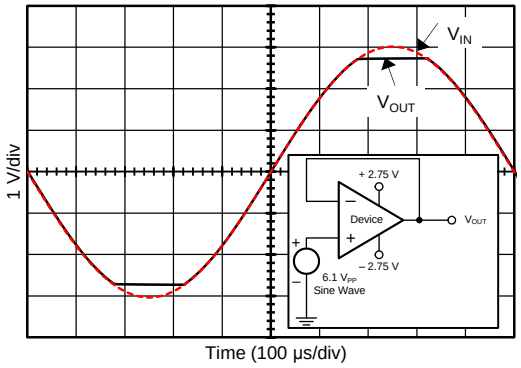
Typical Characteristics (continued)

at T_A = 25°C, V_S = 5.5 V, R_L = 10 kΩ connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2, (unless otherwise noted)



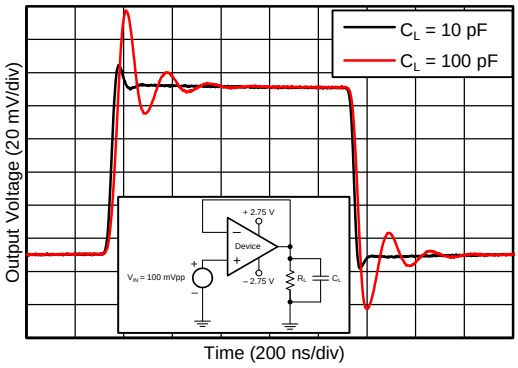
V+ = 2.75 V, V– = –2.75 V, G = –1 V/V

図 7. Small-Signal Overshoot vs Load Capacitance



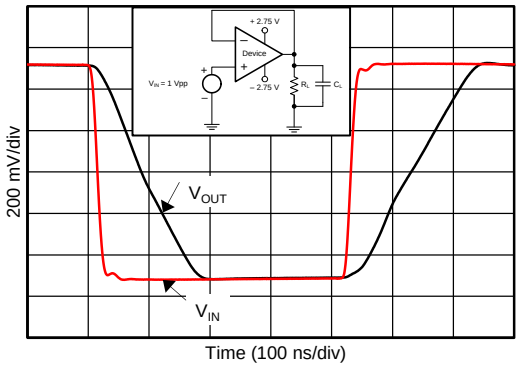
V+ = 2.75 V, V– = –2.75 V

図 8. No Phase Reversal



V+ = 2.75 V, V– = –2.75 V, G = 1 V/V

図 9. Small-Signal Step Response



V+ = 2.75 V, V– = –2.75 V, C_L = 100 pF, G = 1 V/V

図 10. Large-Signal Step Response

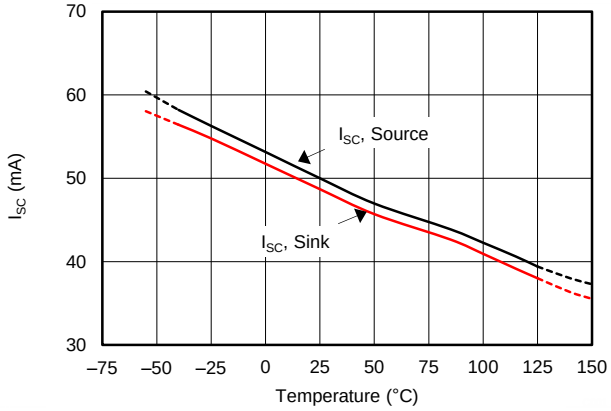
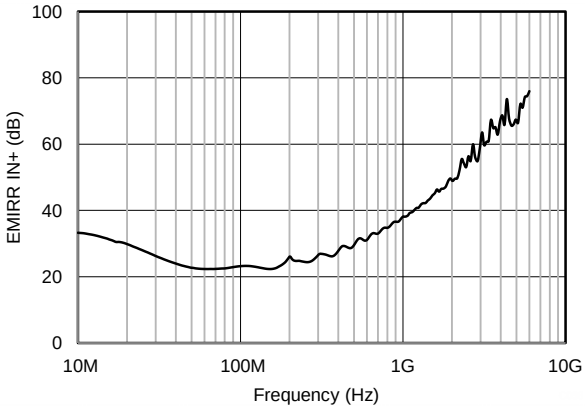


図 11. Short-Circuit Current vs Temperature



P_{RF} = –10 dBm

図 12. Electromagnetic Interference Rejection Ratio Referred to Noninverting Input vs Frequency

Typical Characteristics (continued)

at T_A = 25°C, V_S = 5.5 V, R_L = 10 kΩ connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2, (unless otherwise noted)

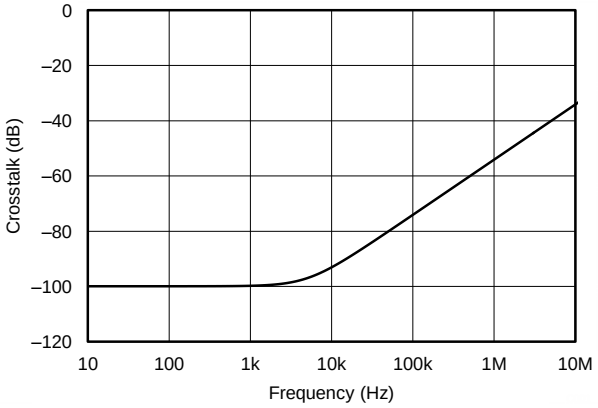


図 13. Channel Separation vs Frequency

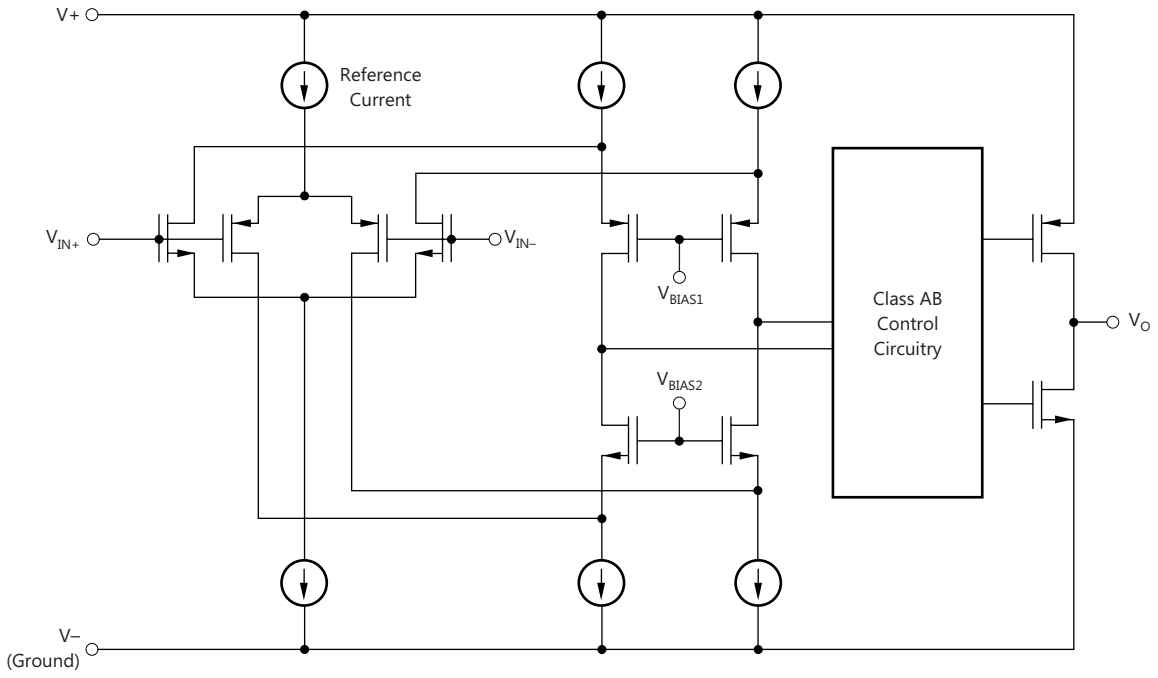
8 Detailed Description

8.1 Overview

The TLVx316-Q1 is a family of low-power, rail-to-rail input and output operational amplifiers. These devices operate from 1.8 V to 5.5 V, are unity-gain stable, and are suitable for a wide range of general-purpose applications. The class AB output stage is capable of driving ≤ 10-kΩ loads connected to any point between V+ and ground. The input common-mode voltage range includes both rails and allows the TLVx316-Q1 to be used in virtually any single-supply application. Rail-to-rail input and output swing significantly increases dynamic range, especially in low-supply applications, and makes them suitable for driving sampling analog-to-digital converters (ADCs).

The TLVx316-Q1 features 10-MHz bandwidth and 6-V/μs slew rate with only 400-μA supply current per channel, providing good ac performance at very-low-power consumption. DC applications are well served with a very-low input noise voltage of 12 nV/√Hz at 1 kHz, low input bias current (5 pA), and an input offset voltage of 0.5 mV (typical).

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Operating Voltage

The TLVx316-Q1 operational amplifiers are fully specified and ensured for operation from 1.8 V to 5.5 V. In addition, many specifications apply from –40°C to +125°C. Parameters that vary significantly with operating voltages or temperature are illustrated in the *Typical Characteristics* section.

8.3.2 Rail-to-Rail Input

The input common-mode voltage range of the TLVx316-Q1 extends 200 mV beyond the supply rails for supply voltages greater than 2.5 V. This performance is achieved with a complementary input stage: an N-channel input differential pair in parallel with a P-channel differential pair, as shown in the *Functional Block Diagram*. The N-channel pair is active for input voltages close to the positive rail, typically (V+) – 1.4 V to 200 mV above the positive supply, whereas the P-channel pair is active for inputs from 200 mV below the negative supply to approximately (V+) – 1.4 V. There is a small transition region, typically (V+) – 1.2 V to (V+) – 1 V, in which both pairs are on. This 200-mV transition region can vary up to 200 mV with process variation. Thus, the transition region (both stages on) can range from (V+) – 1.4 V to (V+) – 1.2 V on the low end, up to (V+) – 1 V to (V+) – 0.8 V on the high end. Within this transition region, PSRR, CMRR, offset voltage, offset drift, and THD can be degraded compared to device operation outside this region.

8.3.3 Rail-to-Rail Output

Designed as a low-power, low-voltage operational amplifier, the TLVx316-Q1 delivers a robust output drive capability. A class AB output stage with common-source transistors is used to achieve full rail-to-rail output swing capability. For resistive loads of 10 kΩ, the output swings typically to within 30 mV of either supply rail regardless of the power-supply voltage applied. Different load conditions change the ability of the amplifier to swing close to the rails; see .

8.3.4 Common-Mode Rejection Ratio (CMRR)

CMRR for the TLVx316-Q1 is specified in two ways so the best match for a given application can be selected. The *Electrical Characteristics* table provides the CMRR of the device in the common-mode range below the transition region [V_{CM} < (V+) – 1.4 V]. This specification is the best indicator of device capability when the application requires using one of the differential input pairs. The CMRR over the entire common-mode range is specified at V_{CM} = –0.2 V to 5.7 V for V_S = 5.5 V. This last value includes the variations through the transition region.

8.3.5 Capacitive Load and Stability

The TLVx316-Q1 is designed for applications where driving a capacitive load is required. As with all operational amplifiers, there may be specific instances where the TLVx316-Q1 can become unstable. The particular operational amplifier circuit configuration, layout, gain, and output loading are some of the factors to consider when establishing whether or not an amplifier is stable in operation. An operational amplifier in the unity-gain (1 V/V) buffer configuration that drives a capacitive load exhibits a greater tendency to be unstable than an amplifier operated at a higher noise gain. The capacitive load, in conjunction with the operational amplifier output resistance, creates a pole within the feedback loop that degrades the phase margin. The degradation of the phase margin increases when the capacitive loading increases. For a conservative best practice, designing for 25% overshoot (40° phase margin) provides improved stability over process variations. The equivalent series resistance (ESR) of some very-large capacitors (C_L capacitors with a value greater than 1 μF) is sufficient to alter the phase characteristics in the feedback loop such that the amplifier remains stable. Increasing the amplifier closed-loop gain allows the amplifier to drive increasingly larger capacitance. This increased capability is evident when observing the overshoot response of the amplifier at higher voltage gains, as shown in 図 7 (G = –1 V/V).

Feature Description (continued)

One technique for increasing the capacitive load drive capability of the amplifier operating in a unity-gain configuration is to insert a small resistor (typically 10-Ω to 20-Ω) in series with the output, as shown in 図 14. This resistor significantly reduces the overshoot and ringing associated with large capacitive loads. One possible problem with this technique, however, is that a voltage divider is created with the added series resistor and any resistor connected in parallel with the capacitive load. The voltage divider introduces a gain error at the output that reduces the output swing.

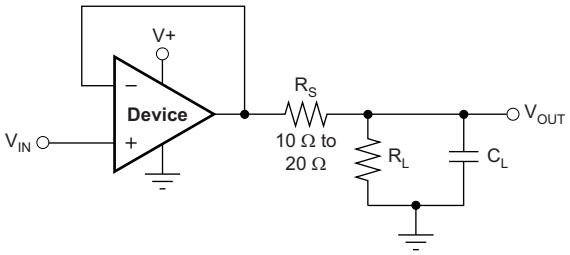


図 14. Improving Capacitive Load Drive

8.3.6 EMI Susceptibility and Input Filtering

Operational amplifiers vary with regard to the susceptibility of the device to electromagnetic interference (EMI). If conducted EMI enters the operational amplifier, the dc offset measured at the amplifier output can shift from the nominal value when EMI is present. This shift is a result of signal rectification associated with the internal semiconductor junctions. Although EMI can affect all operational amplifier pin functions, the signal input pins are likely to be the most susceptible. The TLVx316-Q1 operational amplifier family incorporates an internal input low-pass filter that reduces the amplifier response to EMI. This filter provides both common-mode and differential-mode filtering. The filter is designed for a cutoff frequency of approximately 80 MHz (–3 dB), with a roll-off of 20 dB per decade.

The immunity of an operational amplifier can be accurately measured and quantified over a broad frequency spectrum extending from 10 MHz to 6 GHz. The EMI rejection ratio (EMIRR) metric allows operational amplifiers to be directly compared by the EMI immunity. 図 12 illustrates the results of this testing on the TLVx316-Q1. Detailed information can be found in *EMI Rejection Ratio of Operational Amplifiers*, available for download from www.ti.com.

8.3.7 Overload Recovery

Overload recovery is defined as the time required for the operational amplifier output to recover from a saturated state to a linear state. The output devices of the operational amplifier enter a saturation region when the output voltage exceeds the rated operating voltage, either because of the high input voltage or the high gain. After the device enters the saturation region, the charge carriers in the output devices require time to return back to the linear state. After the charge carriers return back to the linear state, the device begins to slew at the specified slew rate. Thus, the propagation delay in case of an overload condition is the sum of the overload recovery time and the slew time. The overload recovery time for the TLVx316-Q1 is approximately 300 ns.

8.4 Device Functional Modes

The TLVx316-Q1 family has a single functional mode. These devices are powered on as long as the power-supply voltage is between 1.8 V (±0.9 V) and 5.5 V (±2.75 V).

9 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The TLV316-Q1, TLV2316-Q1, and TLV4316-Q1 devices are powered on when the supply is connected. The devices can operate as a single-supply operational amplifier or a dual-supply amplifier, depending on the application.

9.2 System Examples

When receiving low-level signals, the device often requires limiting the bandwidth of the incoming signals into the system. The simplest way to establish this limited bandwidth is to place an RC filter at the noninverting pin of the amplifier, as shown in 図 15.

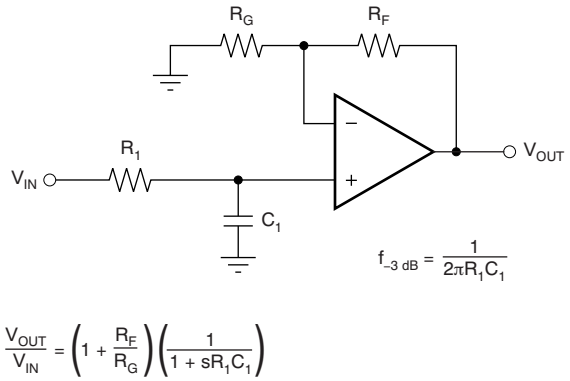


図 15. Single-Pole, Low-Pass Filter

If even more attenuation is needed, the device requires a multiple-pole filter. The Sallen-Key filter can be used for this task, as shown in 図 16. For best results, the amplifier must have a bandwidth that is eight to ten times the filter frequency bandwidth. Failure to follow this guideline can result in a phase shift of the amplifier.

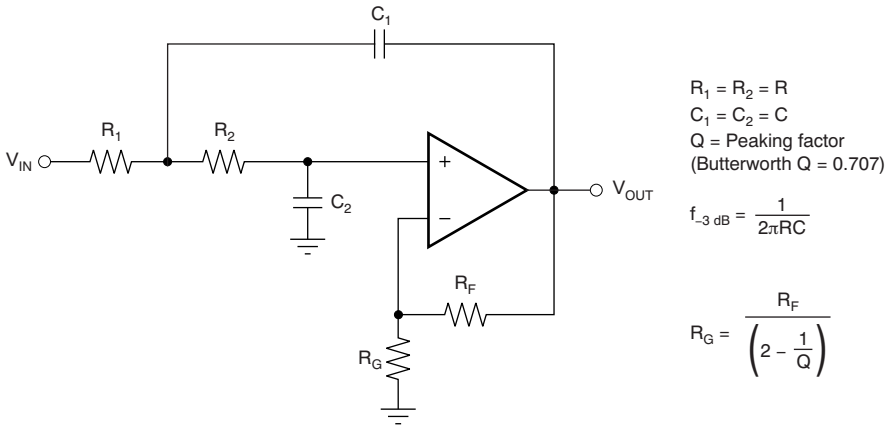


図 16. Two-Pole, Low-Pass, Sallen-Key Filter

10 Power Supply Recommendations

The TLVx316-Q1 family is specified for operation from 1.8 V to 5.5 V (±0.9 V to ±2.75 V); many specifications apply from –40°C to +125°C. The *Typical Characteristics* section presents parameters that can exhibit significant variance with regard to operating voltage or temperature.

> **注意**
>
> Supply voltages larger than 7 V can permanently damage the device; see the *Absolute Maximum Ratings* table.

Place 0.1-μF bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or high-impedance power supplies. For more detailed information on bypass capacitor placement, see the *Layout Guidelines* section.

10.1 Input and ESD Protection

The TLVx316-Q1 incorporates internal ESD protection circuits on all pins. For input and output pins, this protection primarily consists of current-steering diodes connected between the input and power-supply pins. These ESD protection diodes provide in-circuit, input overdrive protection, as long as the current is limited to 10 mA, as stated in the *Absolute Maximum Ratings* table. 図 17 shows how a series input resistor can be added to the driven input to limit the input current. The added resistor contributes thermal noise at the amplifier input and the value must be kept to a minimum in noise-sensitive applications.

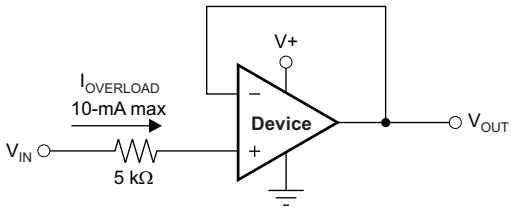


図 17. Input Current Protection

11 Layout

11.1 Layout Guidelines

For best operational performance of the device, use good PCB layout practices, including:

- Noise can propagate into analog circuitry through the power pins of the circuit as a whole and the operational amplifier. Bypass capacitors reduce the coupled noise by providing low-impedance power sources local to the analog circuitry.
  - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as close to the device as possible. A single bypass capacitor from V+ to ground is applicable for single-supply applications.
- Separate grounding for analog and digital portions of the circuitry is one of the simplest and most effective methods of noise suppression. One or more layers on multilayer PCBs are typically devoted to ground planes. A ground plane helps distribute heat and reduces EMI noise pickup. Take care to physically separate digital and analog grounds, paying attention to the flow of the ground current. For more detailed information, see *Circuit Board Layout Techniques*.
- To reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible. If these traces cannot be kept separate, crossing the sensitive trace perpendicularly is much better than crossing in parallel with the noisy trace.
- Place the external components as close to the device as possible. Keeping R_F and R_G close to the inverting input minimizes parasitic capacitance, as shown in 図 18.
- Keep the length of input traces as short as possible. Remember that the input traces are the most sensitive part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring can significantly reduce leakage currents from nearby traces that are at different potentials.

11.2 Layout Example

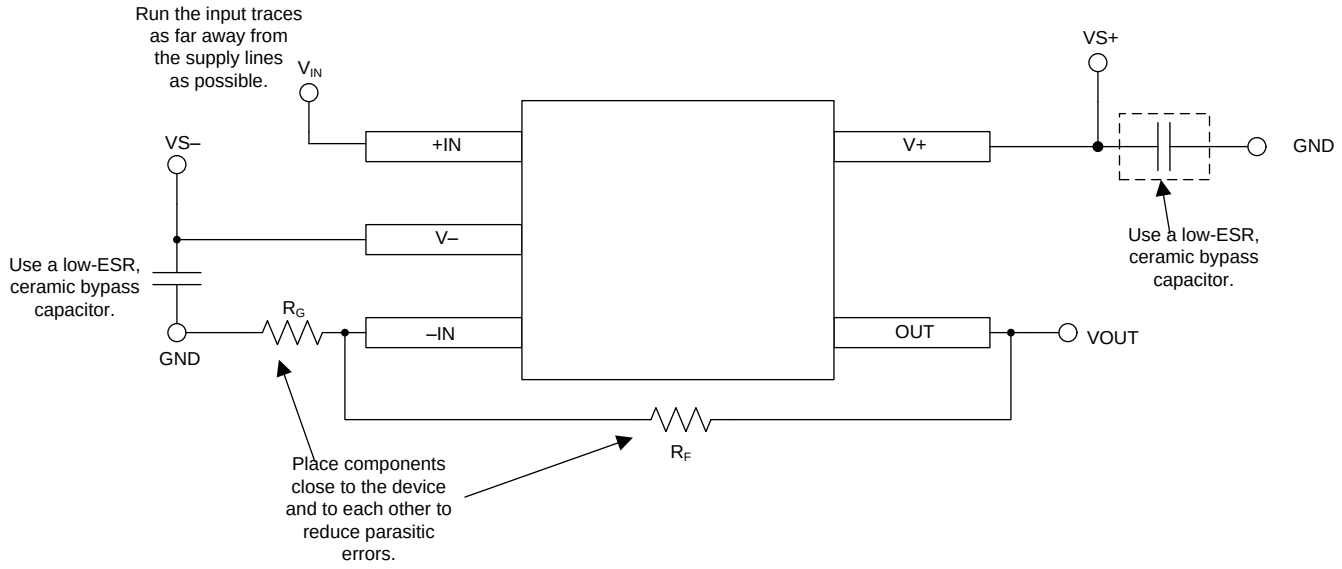


図 18. Operational Amplifier Board Layout for a Noninverting Configuration

12 デバイスおよびドキュメントのサポート

12.1 ドキュメントのサポート

12.1.1 関連資料

『TLVx313 低消費電力、レール・ツー・レール入出力、オフセット標準値500μV、1MHzの低コスト・システム用オペアンプ』

『TLVx314 3MHz、低消費電力、EMIフィルタ内蔵、RRIOオペアンプ』

『オペアンプのEMI除去率』

『QFN/SONのPCB実装』

『クワッド・フラットパック・リード端子なしロジック・パッケージ』

『基板のレイアウト技法』

『シングル・エンド入力から差動出力への変換回路のリファレンス・デザイン』

12.2 関連リンク

次の表に、クイック・アクセス・リンクを示します。カテゴリには、技術資料、サポートおよびコミュニティ・リソース、ツールとソフトウェア、およびご注文へのクイック・アクセスが含まれます。

表 2. 関連リンク

製品	プロダクト・フォルダ	ご注文はこちら	技術資料	ツールとソフトウェア	サポートとコミュニティ
TLV316-Q1	ここをクリック	ここをクリック	ここをクリック	ここをクリック	ここをクリック
TLV2316-Q1	ここをクリック	ここをクリック	ここをクリック	ここをクリック	ここをクリック
TLV4316-Q1	ここをクリック	ここをクリック	ここをクリック	ここをクリック	ここをクリック

12.3 コミュニティ・リソース

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™オンライン・コミュニティ ***TIのE2E (Engineer-to-Engineer) コミュニティ。***エンジニア間の共同作業を促進するために開設されたものです。e2e.ti.comでは、他のエンジニアに質問し、知識を共有し、アイディアを検討して、問題解決に役立てることができます。

設計サポート ***TIの設計サポート*** 役に立つE2Eフォーラムや、設計サポート・ ツールをすばやく見つけることができます。技術サポート用の連絡先情報も参照できます。

12.4 商標

E2E is a trademark of Texas Instruments.

12.5 静電気放電に関する注意事項

すべての集積回路は、適切なESD保護方法を用いて、取扱いと保存を行うようにして下さい。

静電気放電はわずかな性能の低下から完全なデバイスの故障に至るまで、様々な損傷を与えます。高精度の集積回路は、損傷に対して敏感であり、極めてわずかなパラメータの変化により、デバイスに規定された仕様に適合しなくなる場合があります。

12.6 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

13 メカニカル、パッケージ、および注文情報

以降のページには、メカニカル、パッケージ、および注文に関する情報が記載されています。この情報は、そのデバイスについて利用可能な最新のデータです。このデータは予告なく変更されることがあり、ドキュメントが改訂される場合もあります。本データシートのブラウザ版を使用されている場合は、画面左側の説明をご覧ください。

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TLV2316QDGKRQ1	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	16M6	Samples
TLV2316QDGKTQ1	ACTIVE	VSSOP	DGK	8	250	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	16M6	Samples
TLV316QDBVRQ1	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	16ND	Samples
TLV316QDBVTQ1	ACTIVE	SOT-23	DBV	5	250	RoHS & Green	NIPDAU | SN	Level-2-260C-1 YEAR	-40 to 125	16ND	Samples
TLV4316QPWRQ1	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	V4316Q1	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

OTHER QUALIFIED VERSIONS OF TLV2316-Q1, TLV316-Q1, TLV4316-Q1 :

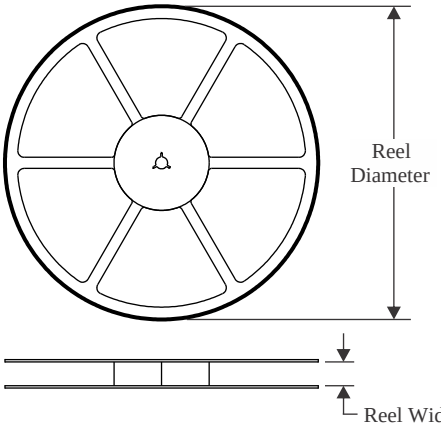
- Catalog : TLV2316, TLV316, TLV4316

NOTE: Qualified Version Definitions:

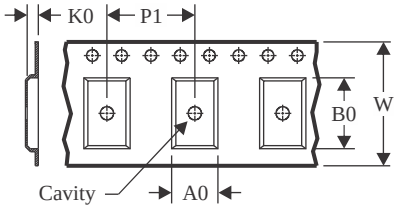
- Catalog - TI's standard catalog product

TAPE AND REEL INFORMATION

REEL DIMENSIONS

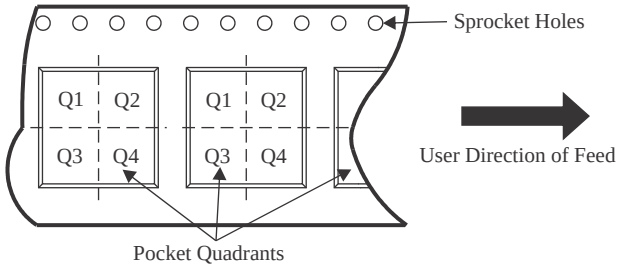


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

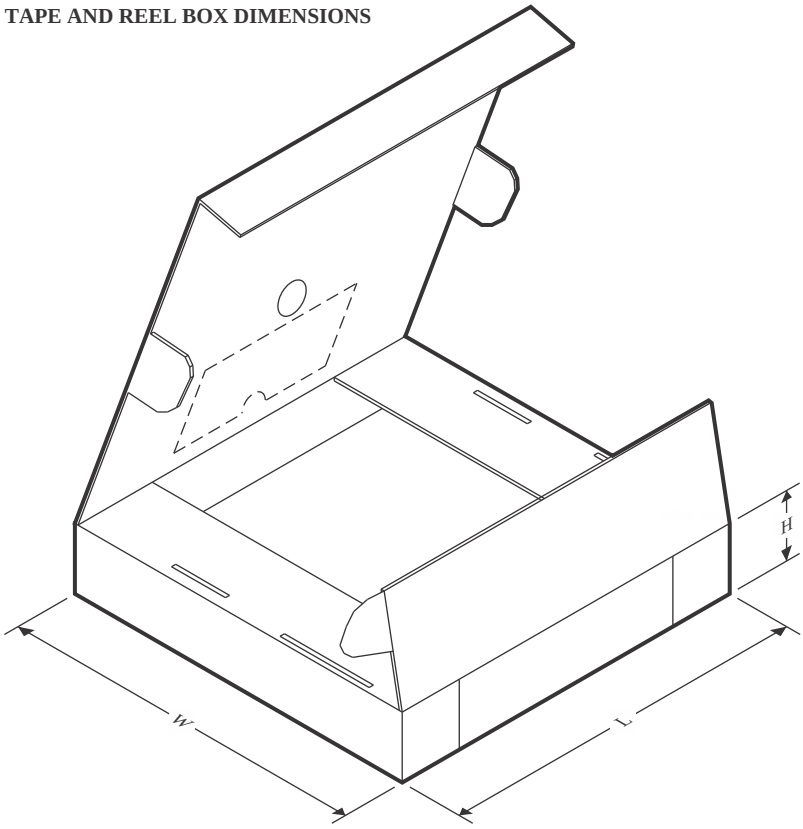
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV2316QDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV2316QDGKTQ1	VSSOP	DGK	8	250	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV316QDBVRQ1	SOT-23	DBV	5	3000	178.0	9.0	3.3	3.2	1.4	4.0	8.0	Q3
TLV316QDBVTQ1	SOT-23	DBV	5	250	178.0	9.0	3.3	3.2	1.4	4.0	8.0	Q3
TLV4316QPWRQ1	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

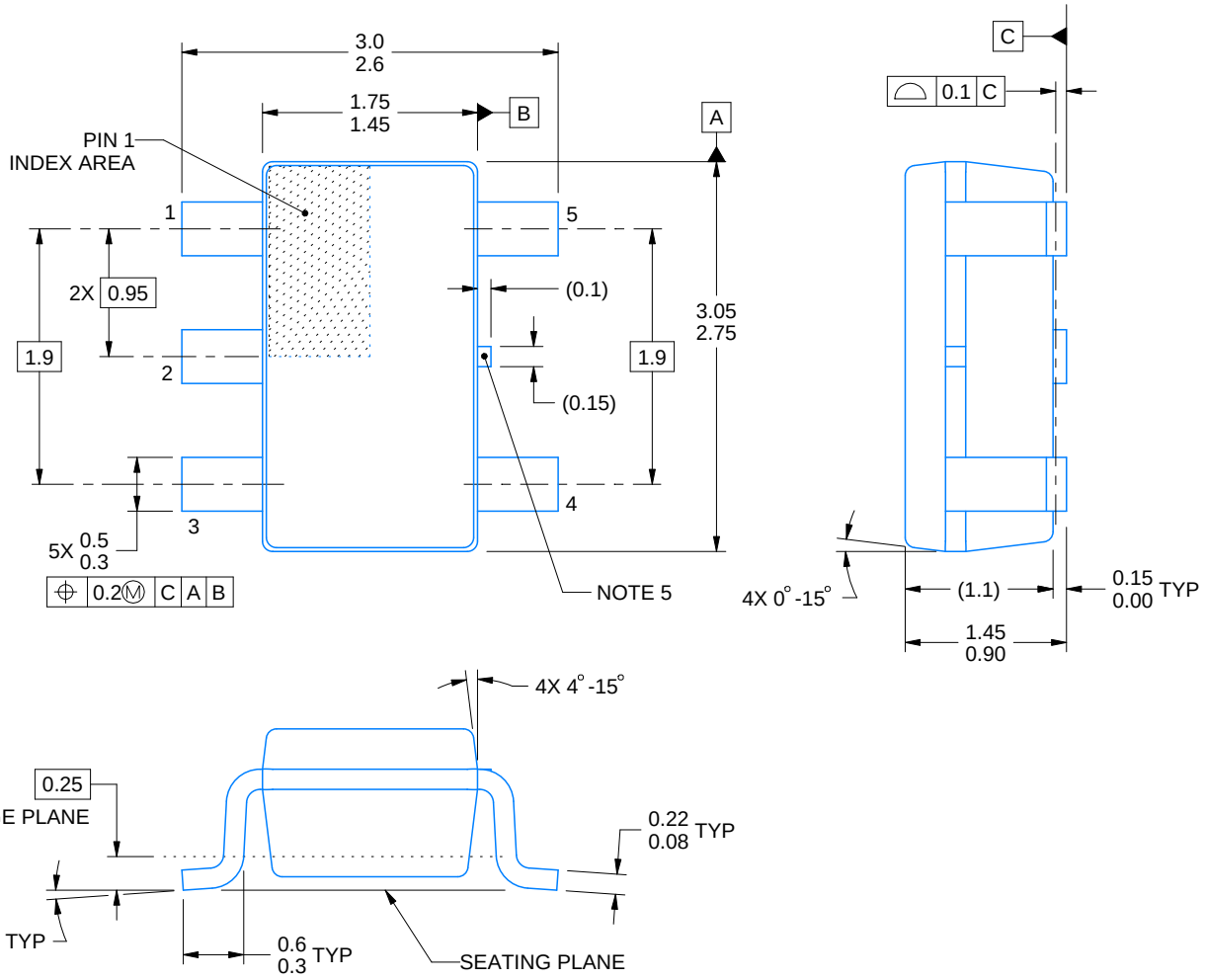
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLV2316QDGKRQ1	VSSOP	DGK	8	2500	366.0	364.0	50.0
TLV2316QDGKTQ1	VSSOP	DGK	8	250	366.0	364.0	50.0
TLV316QDBVRQ1	SOT-23	DBV	5	3000	180.0	180.0	18.0
TLV316QDBVTQ1	SOT-23	DBV	5	250	180.0	180.0	18.0
TLV4316QPWRQ1	TSSOP	PW	14	2000	356.0	356.0	35.0

PACKAGE OUTLINE

DBV0005A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



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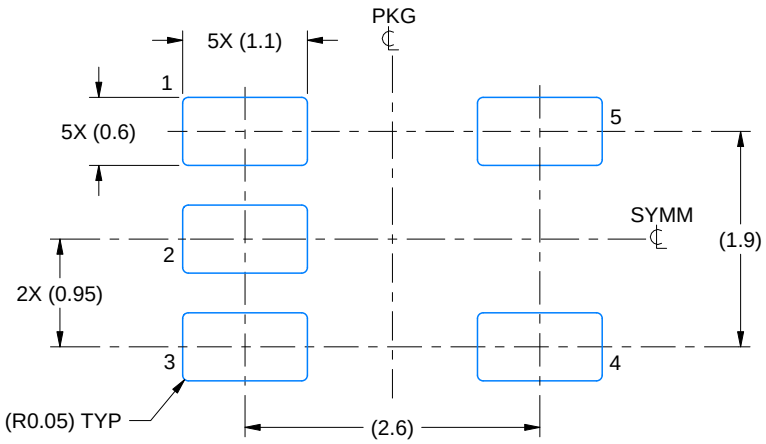
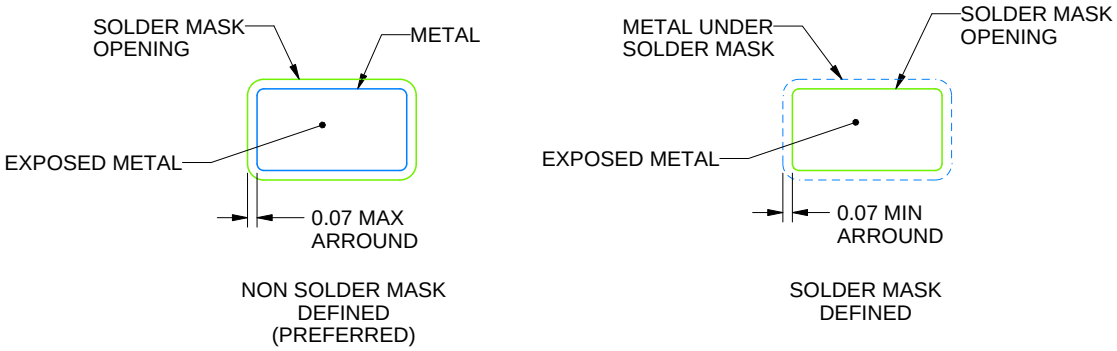
NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Refernce JEDEC MO-178.
4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
5. Support pin may differ or may not be present.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:15X



SOLDER MASK DETAILS

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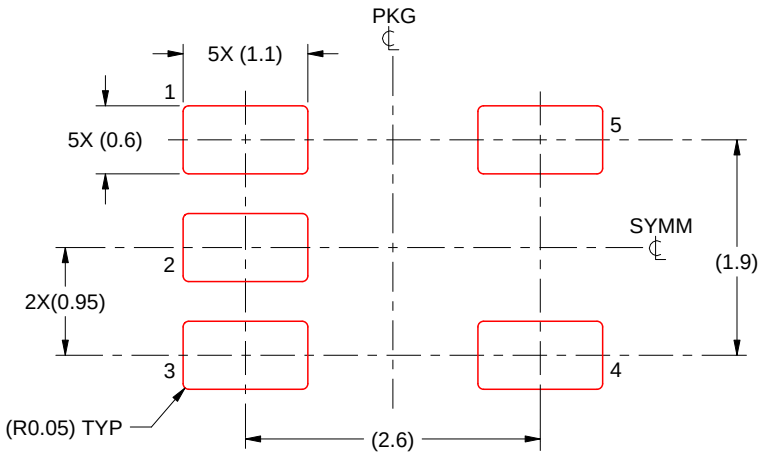
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:15X

4214839/K 08/2024

NOTES: (continued)

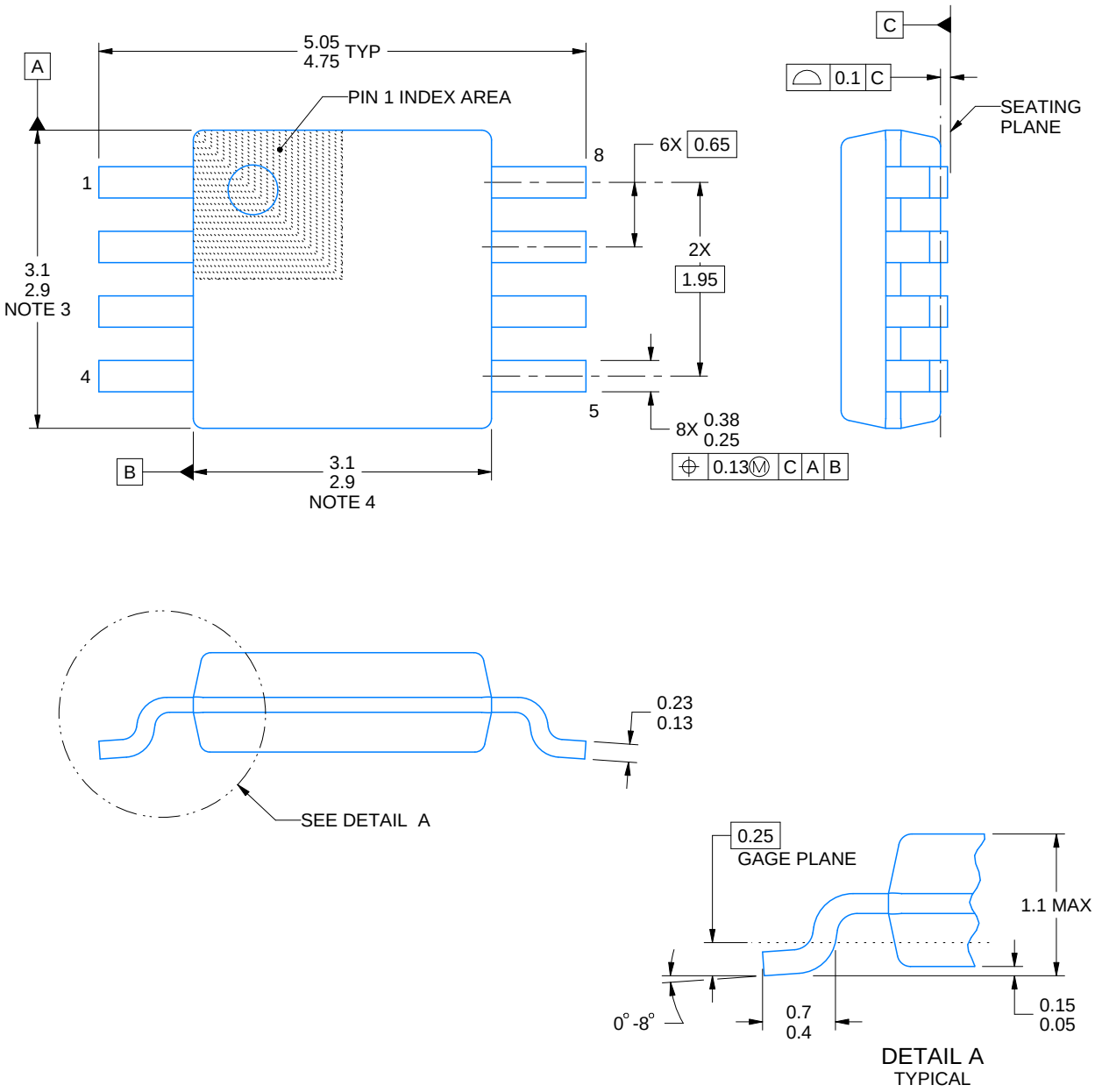
8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

PACKAGE OUTLINE

DGK0008A

VSSOP - 1.1 mm max height

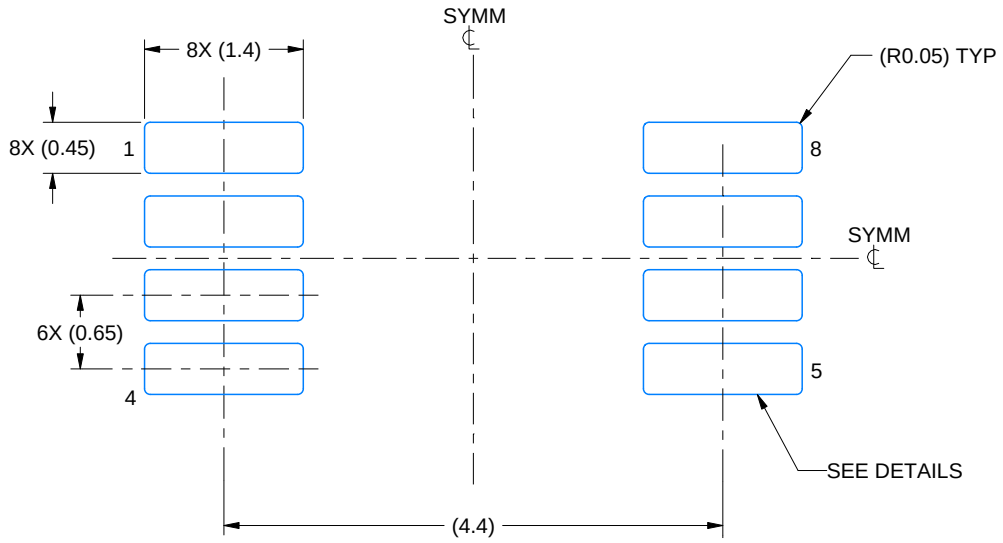
SMALL OUTLINE PACKAGE



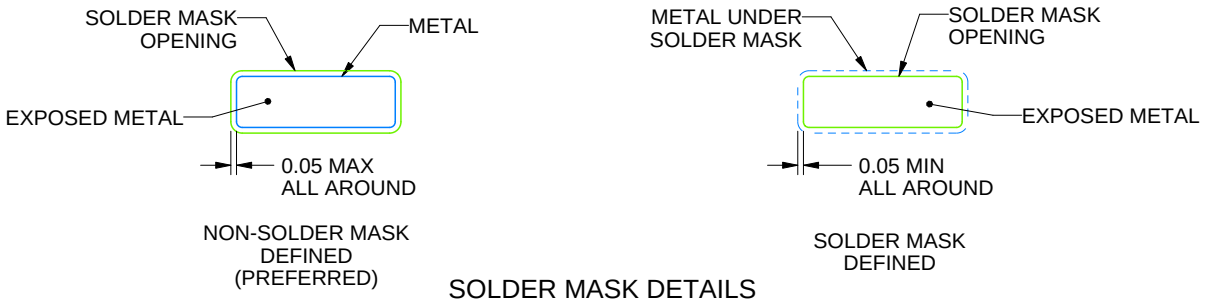
PowerPAD is a trademark of Texas Instruments.

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-187.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 15X

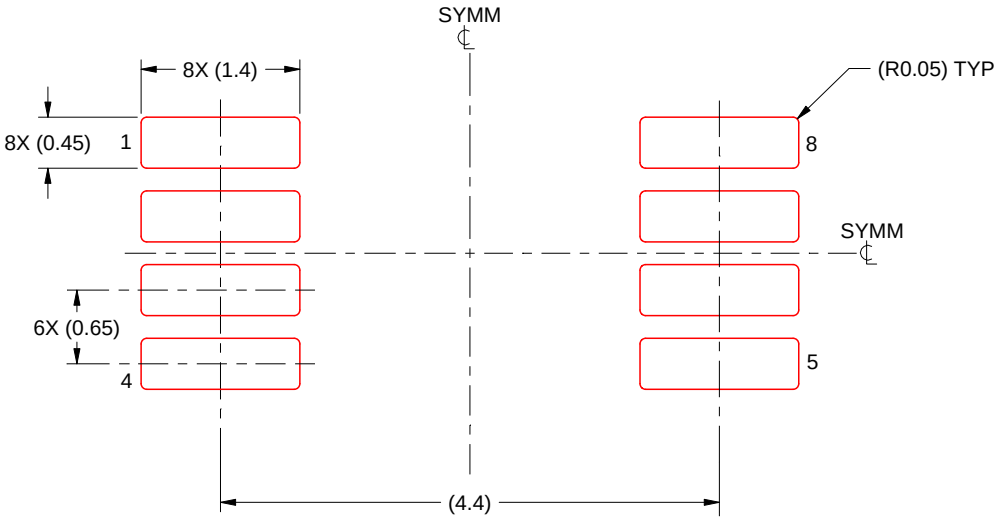


SOLDER MASK DETAILS

4214862/A 04/2023

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
8. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.
9. Size of metal pad may vary due to creepage requirement.



SOLDER PASTE EXAMPLE
SCALE: 15X

4214862/A 04/2023

NOTES: (continued)

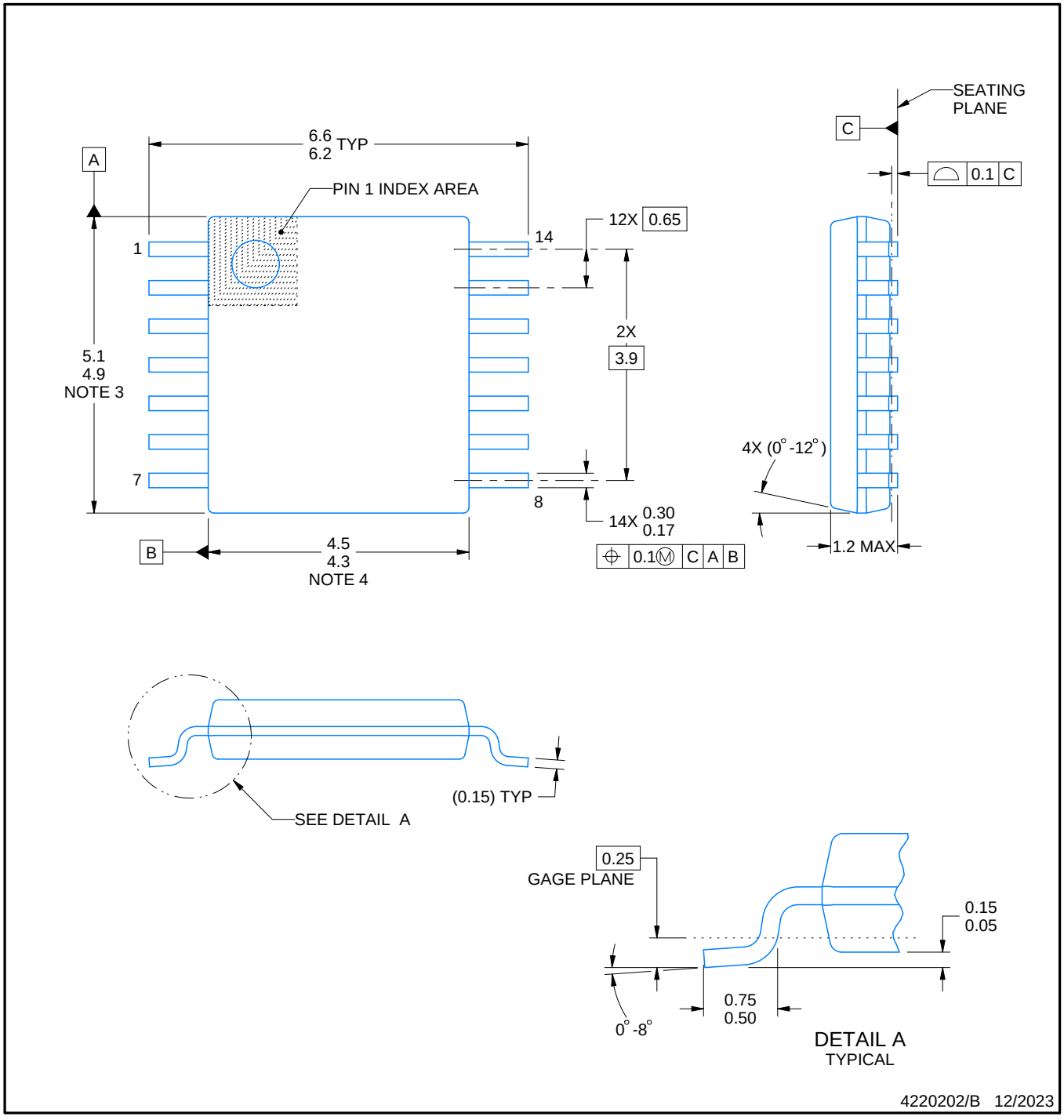
11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
12. Board assembly site may have different recommendations for stencil design.

PACKAGE OUTLINE

PW0014A

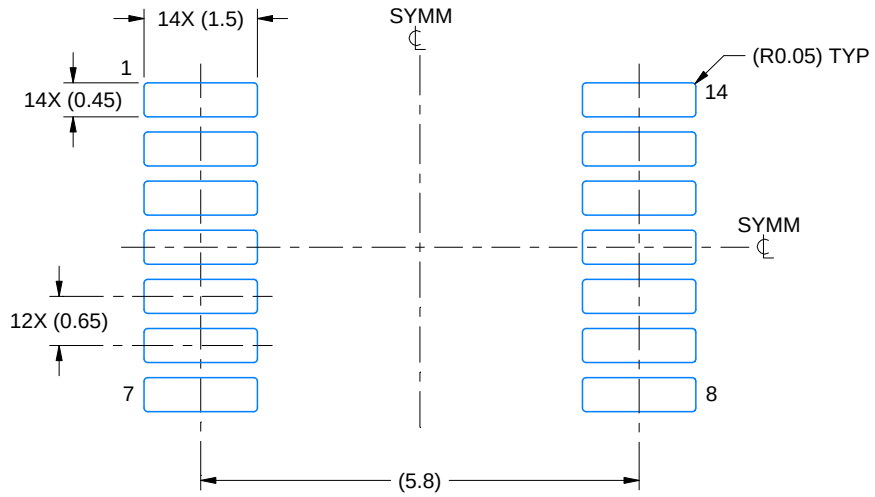
TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE

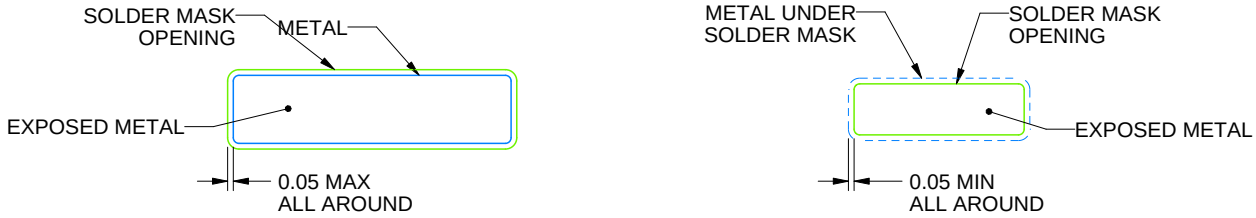


NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X

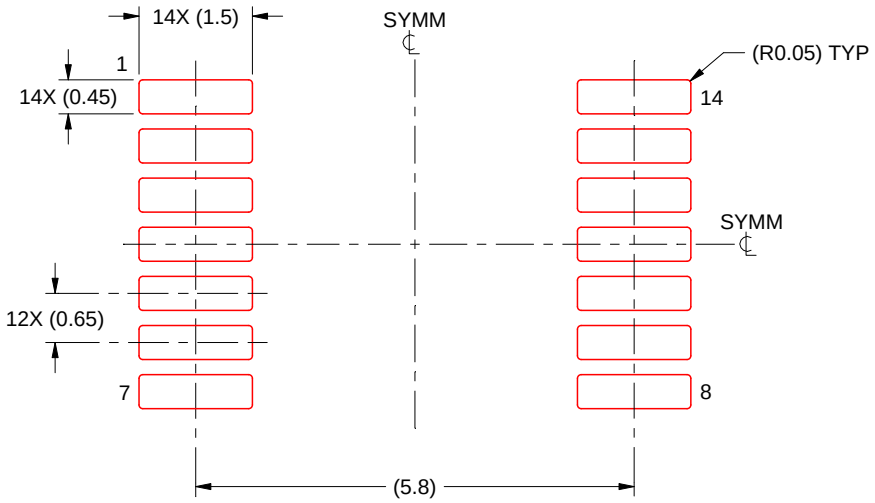


SOLDER MASK DETAILS

4220202/B 12/2023

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4220202/B 12/2023

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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